Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/605,325	LEE, JIAHN-LIN
Examiner	Art Unit
Tai Duong	2871

SEARCHED				
Class	Subclass	Date	Examiner	
		-		
		_		
			-	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST (US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB) See search history printout	8/22/2005	TD